

Abstract Submitted  
for the MAR15 Meeting of  
The American Physical Society

**High Quality Factor MBE-grown Aluminum on Silicon Planar Resonators**<sup>1</sup> ANTHONY MEGRANT, Z. CHEN, B. CHIARO, A. DUNSWORTH, C. QUINTANA, B. CAMPBELL, UC Santa Barbara, R. BARENDS, Y. CHEN, A. FOWLER, Google, Santa Barbara, I.-C. HOI, UC Santa Barbara, E. JEFFREY, Google, Santa Barbara, J. KELLY, UC Santa Barbara, J. MUTUS, Google, Santa Barbara, C. NEILL, P.J.J. O'MALLEY, UC Santa Barbara, P. ROUSHAN, D. SANK, Google, Santa Barbara, A. VAINSENER, J. WENNER, T. WHITE, C. PALMSTROM, UC Santa Barbara, J.M. MARTINIS, University of California and Google, Santa Barbara, A.N. CLELAND, UC Santa Barbara — Linear arrays of planar Xmon qubit circuits fabricated using thin aluminum films on sapphire substrates have resulted in long coherence times and high fidelity gates. Scaling up to larger circuits, including two-dimensional qubit arrays, may however benefit from building circuits on silicon instead of sapphire substrates. I will present recent tests in this direction, reporting on measurements of superconducting coplanar waveguide resonators fabricated using aluminum films deposited on silicon in a molecular beam epitaxy (MBE) system. These resonators exhibit exceptional performance, with quality factors at low temperatures and single photon excitation energies exceeding  $5 \times 10^6$ .

<sup>1</sup>This research was funded by the Office of the Director of National Intelligence (ODNI), Intelligence Advanced Research Projects Activity (IARPA), through the Army Research Office grant W911NF-09-1-0375.

Anthony Megrant  
UC Santa Barbara

Date submitted: 14 Nov 2014

Electronic form version 1.4